

**Search Notes**

Application/Control No.

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Examiner

Nam Huynh

Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

2617

**SEARCHED**

Class	Subclass	Date	Examiner
455	435.1	10/12/2007	NTH
	435.2		
	435.3		
	455		
	458		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See EAST search notes.	10/12/2007	NTH